

Fig. 1

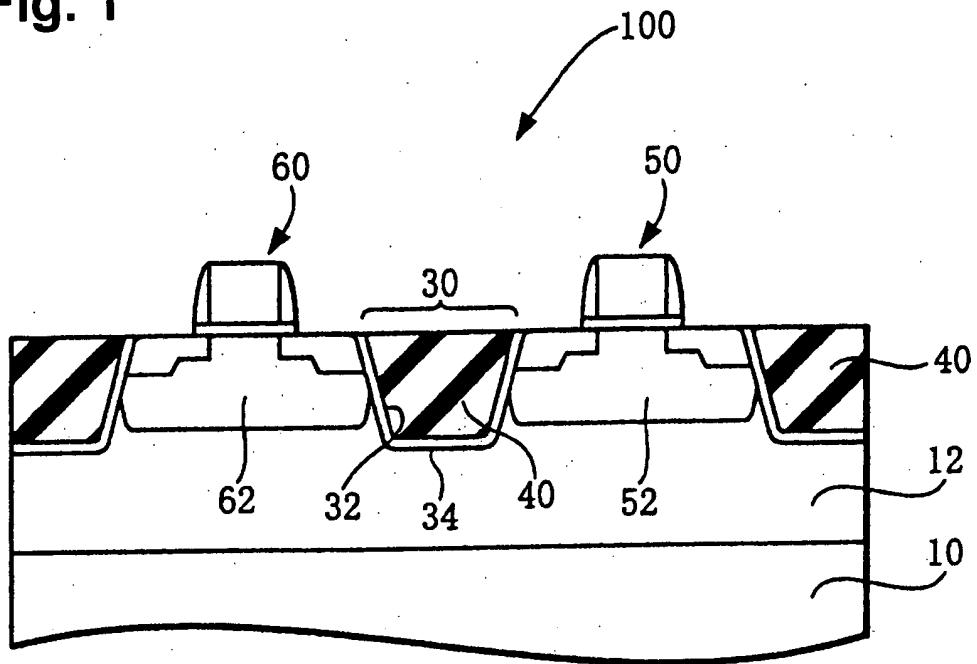


FIG. 1 is a cross-sectional view of a semiconductor device 100.

Fig. 2 (a)

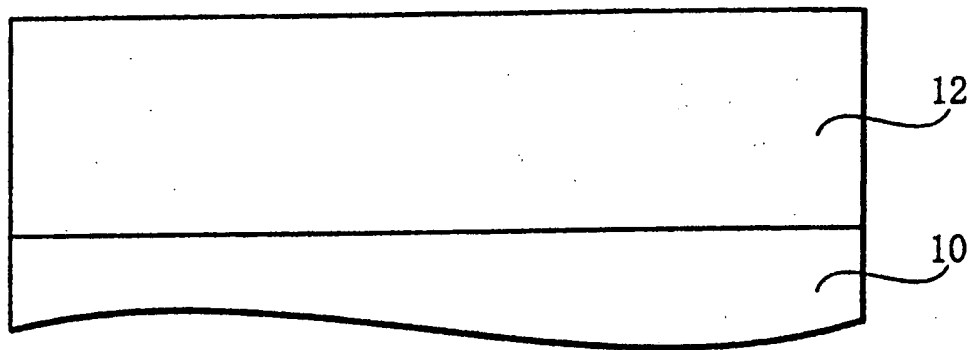


Fig. 2 (b)

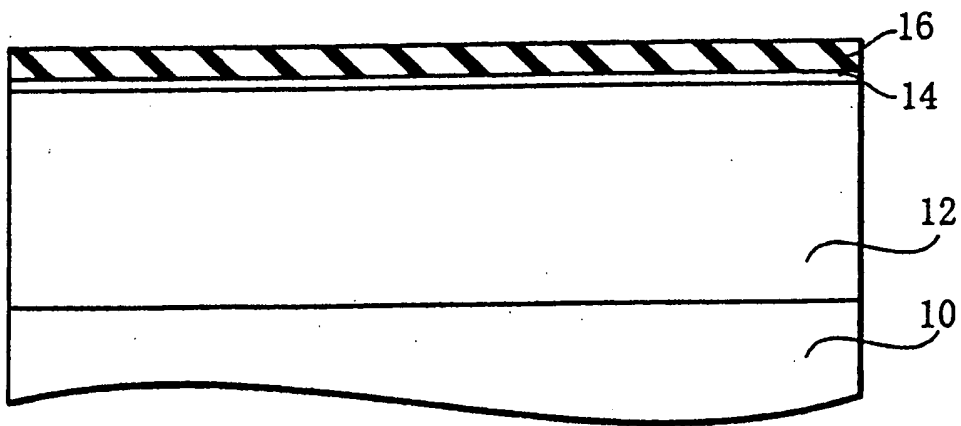


Fig. 3 (a)

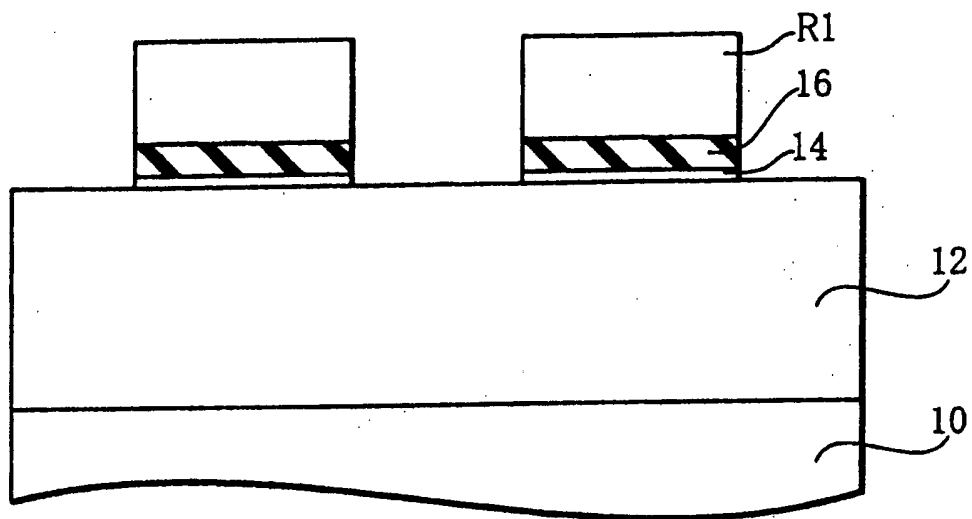


Fig. 3 (b)

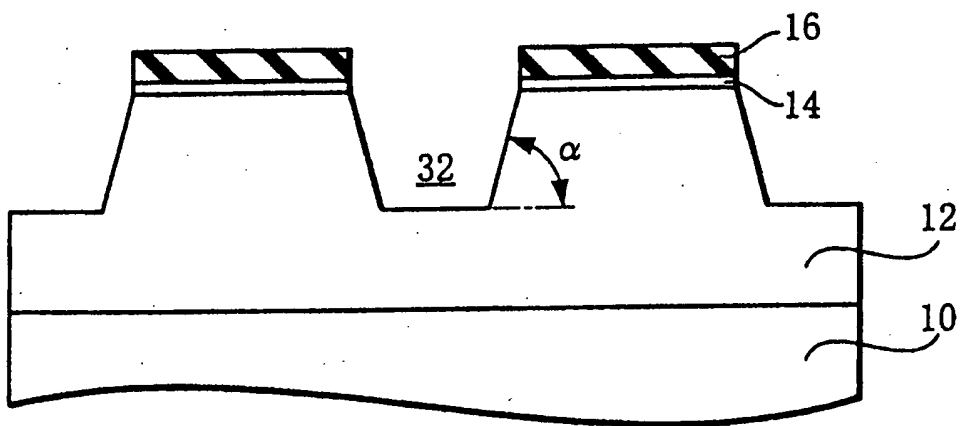


Fig. 4 (a)

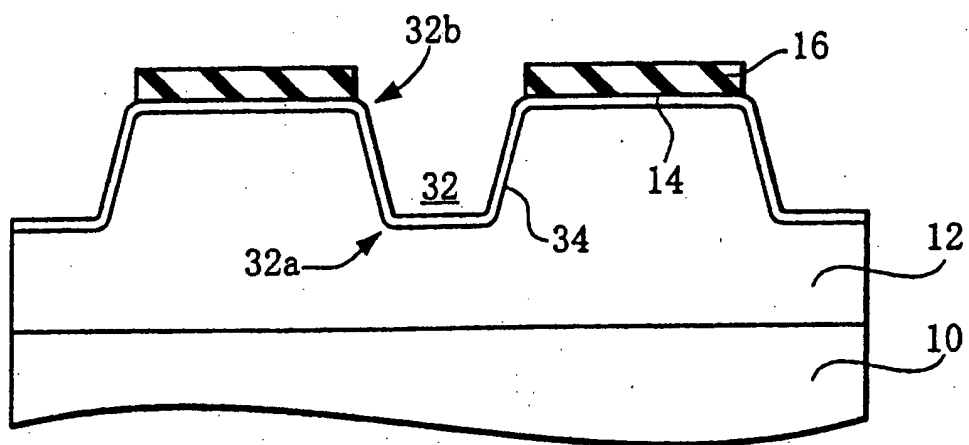


Fig. 4 (b)

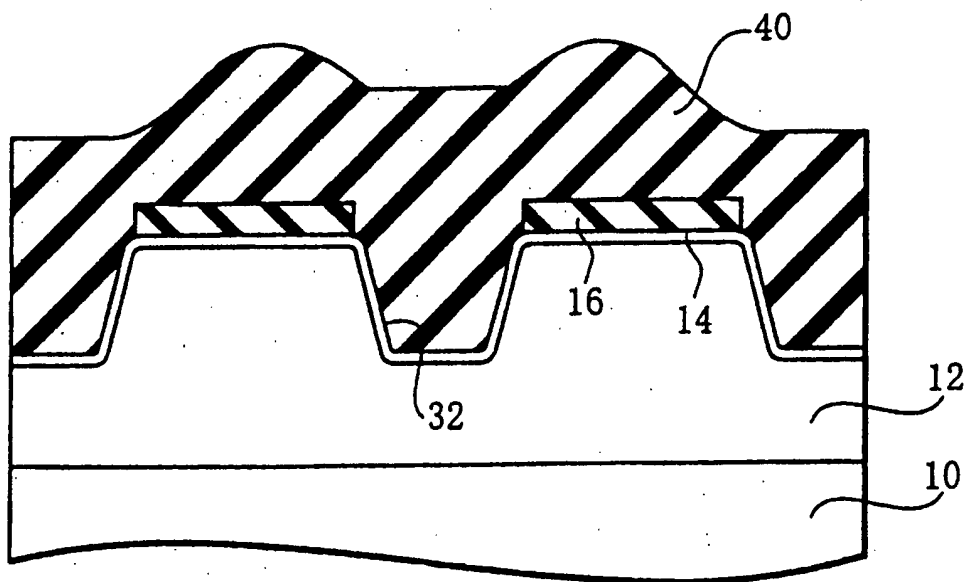


Fig. 5 (a)

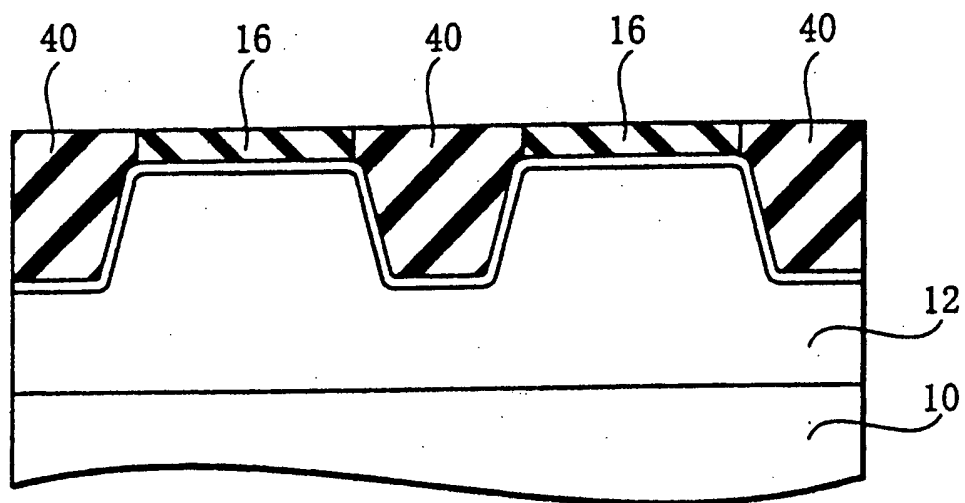


Fig. 5 (b)

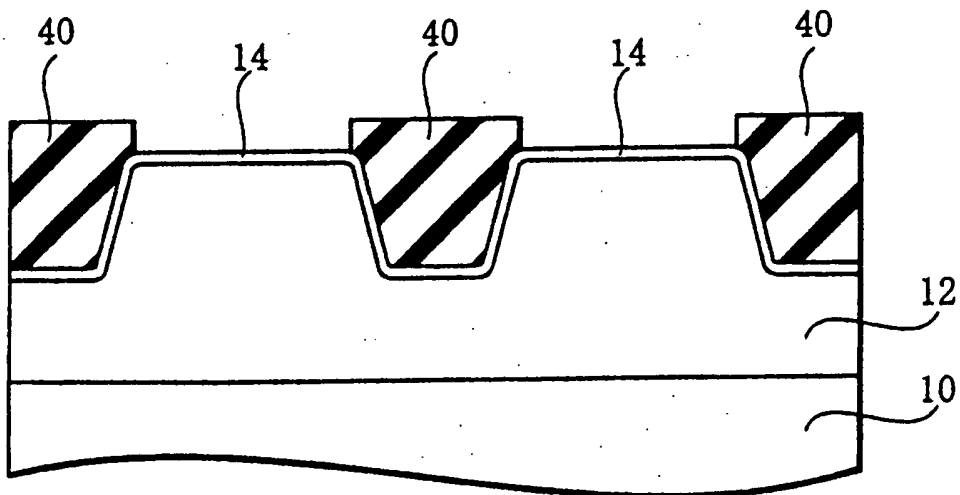


Fig. 6 (a)

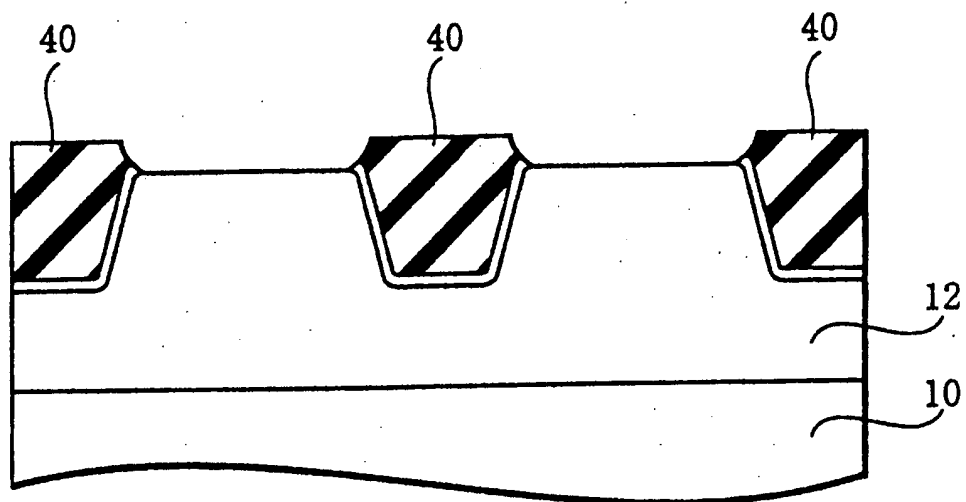


Fig. 6 (b)

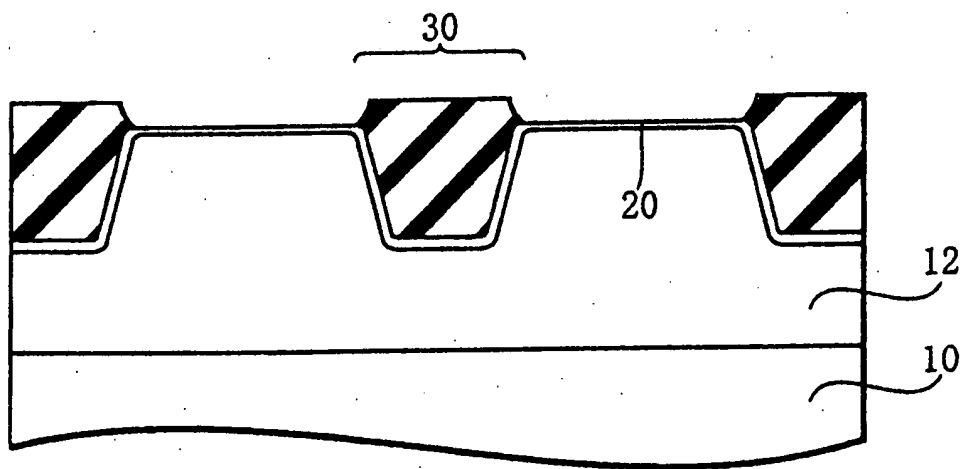


Fig. 7 (a)

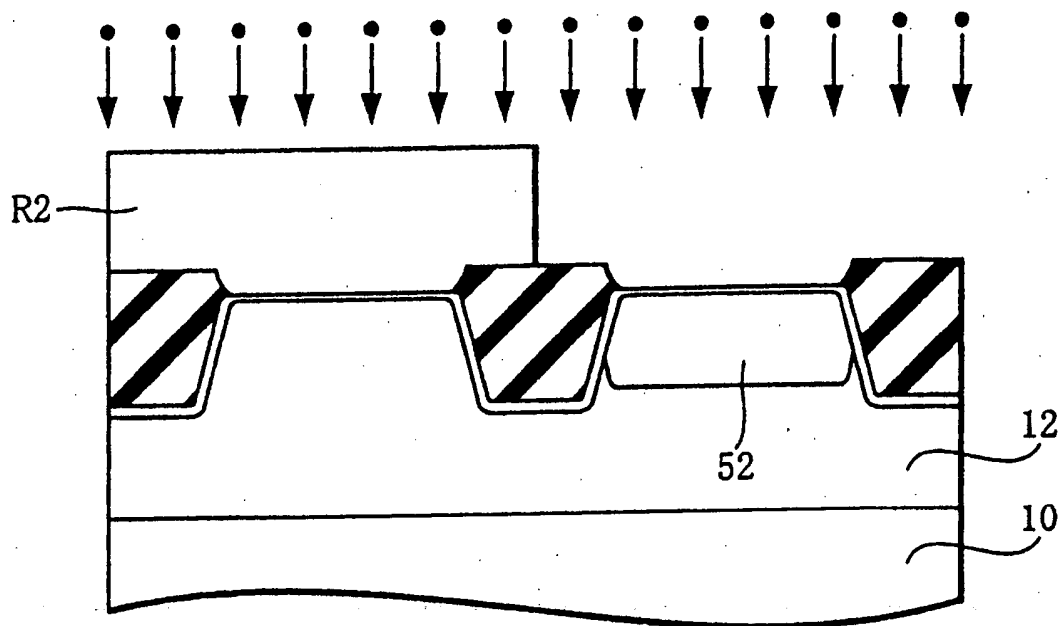


Fig. 7 (b)

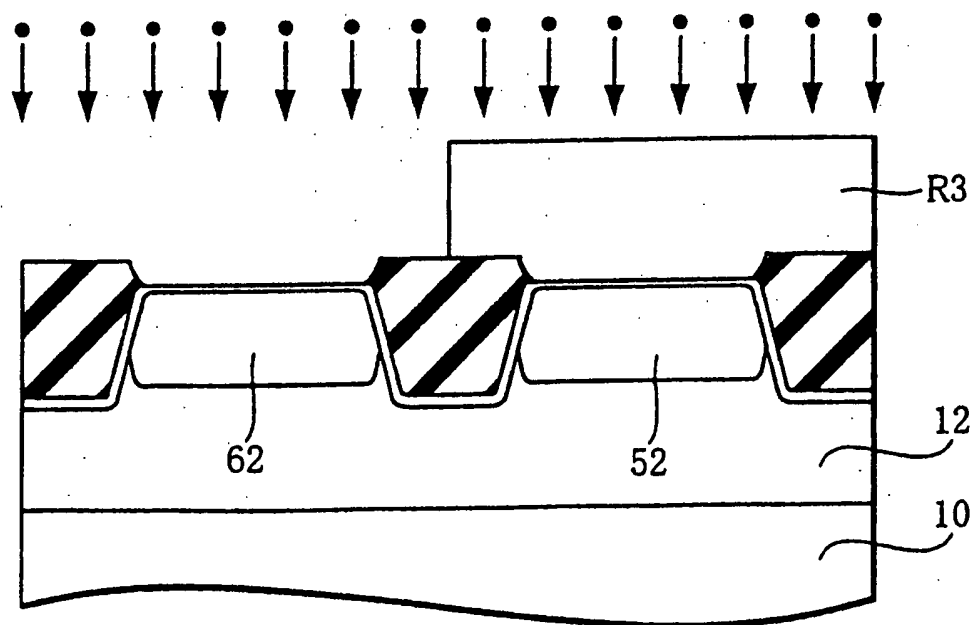


Fig. 8

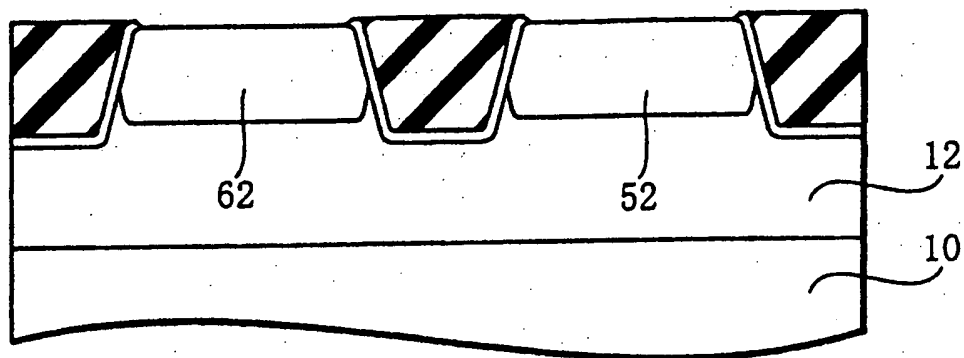


Fig. 9

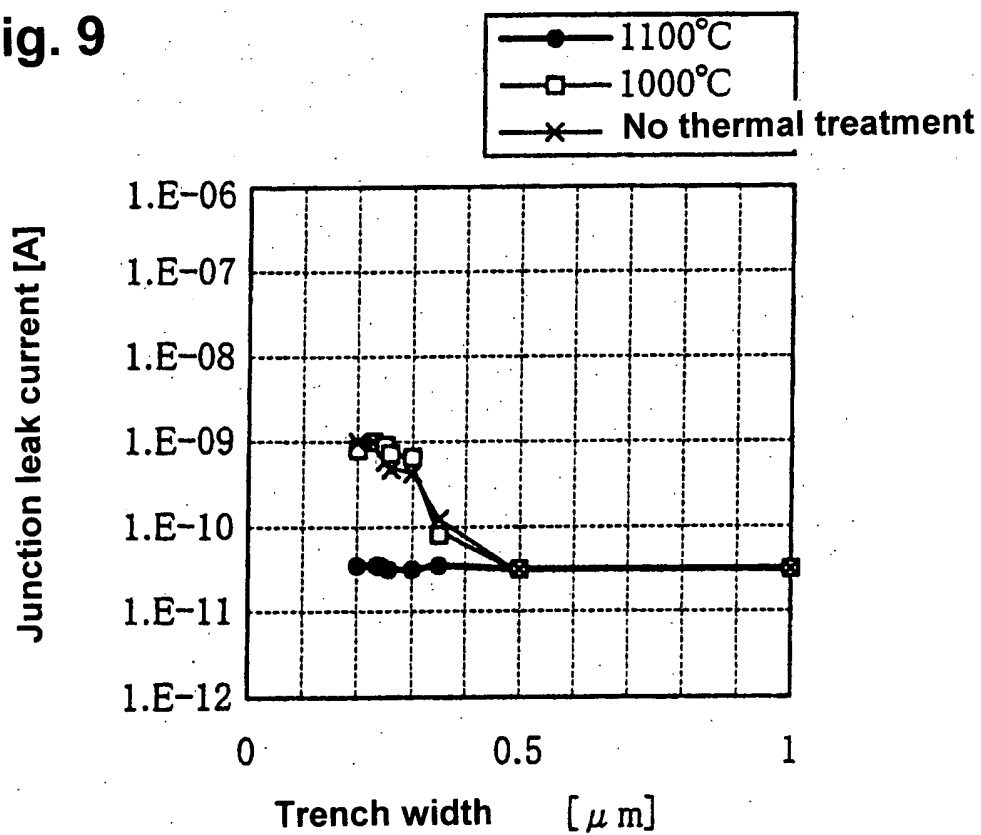


Fig. 10

